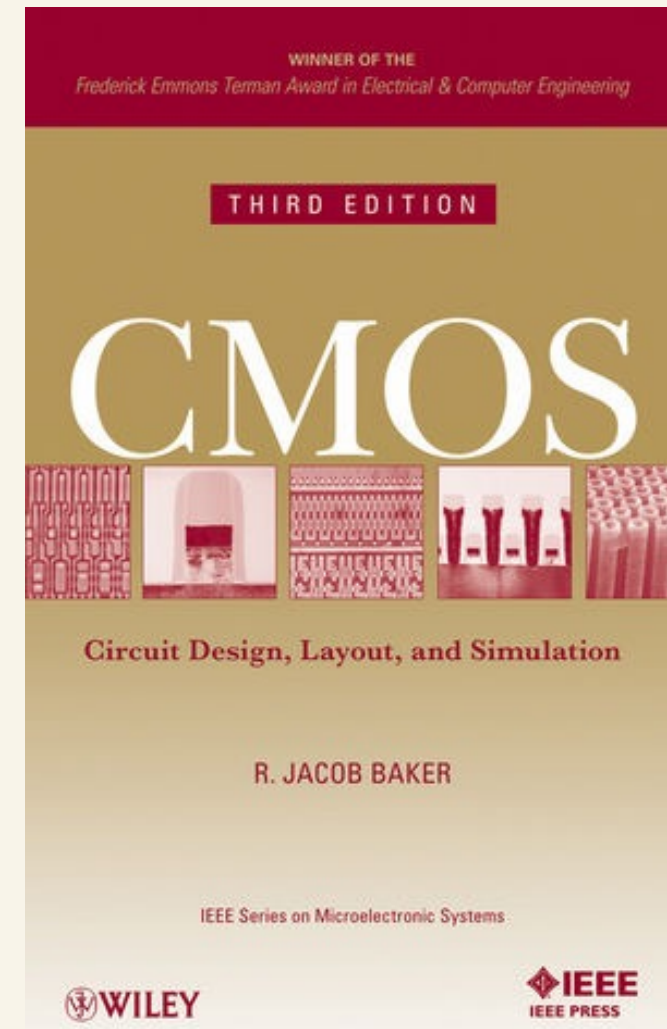


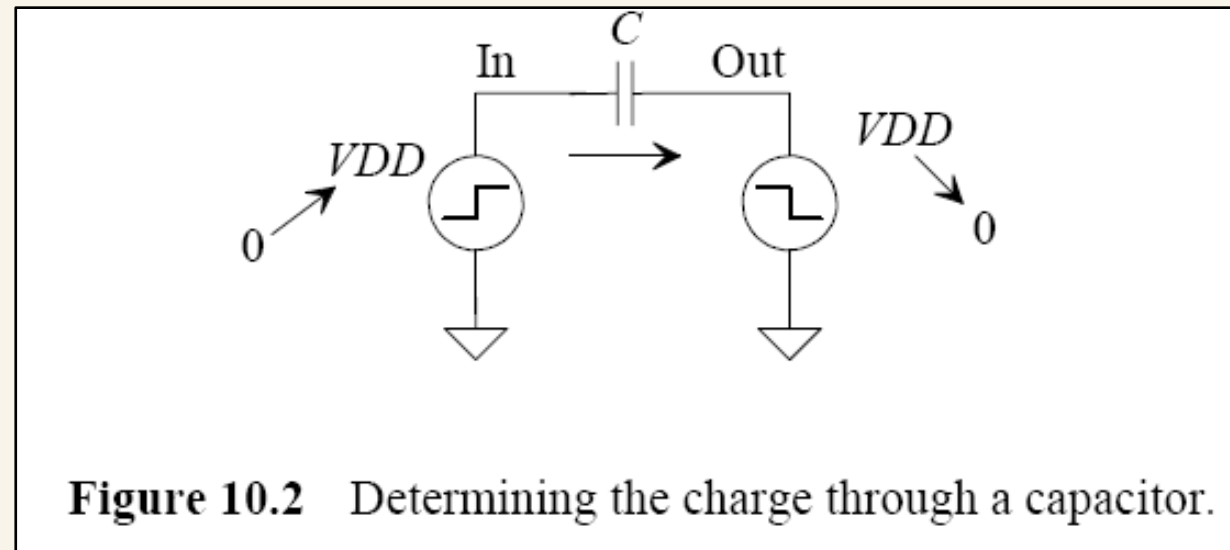
Models for Digital Design

- Miller Capacitance
- The Digital MOSFET Model
- The MOSFET Pass Gate

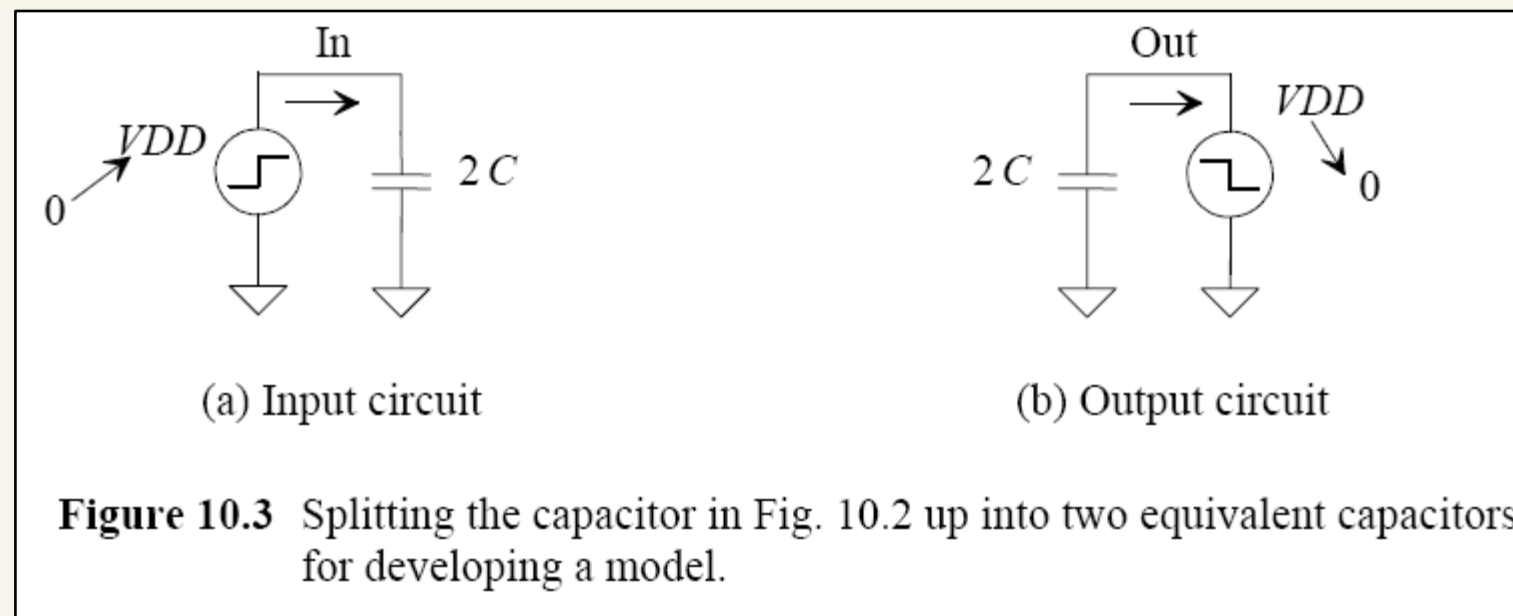
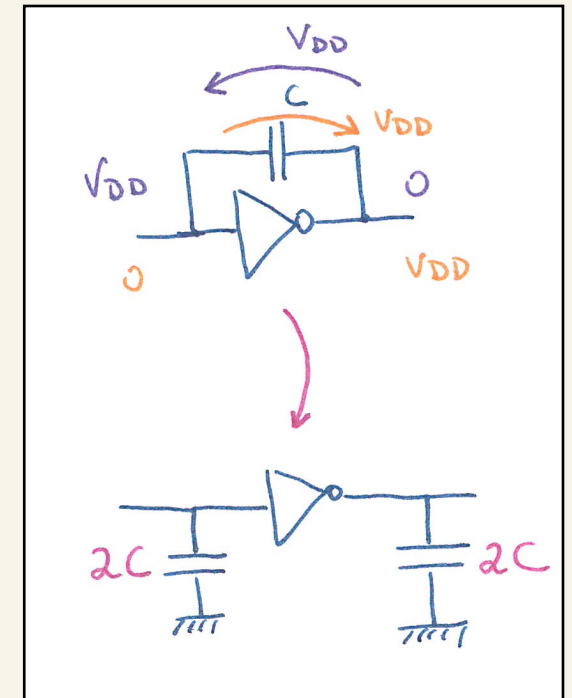


Chap 10

Miller Capacitance

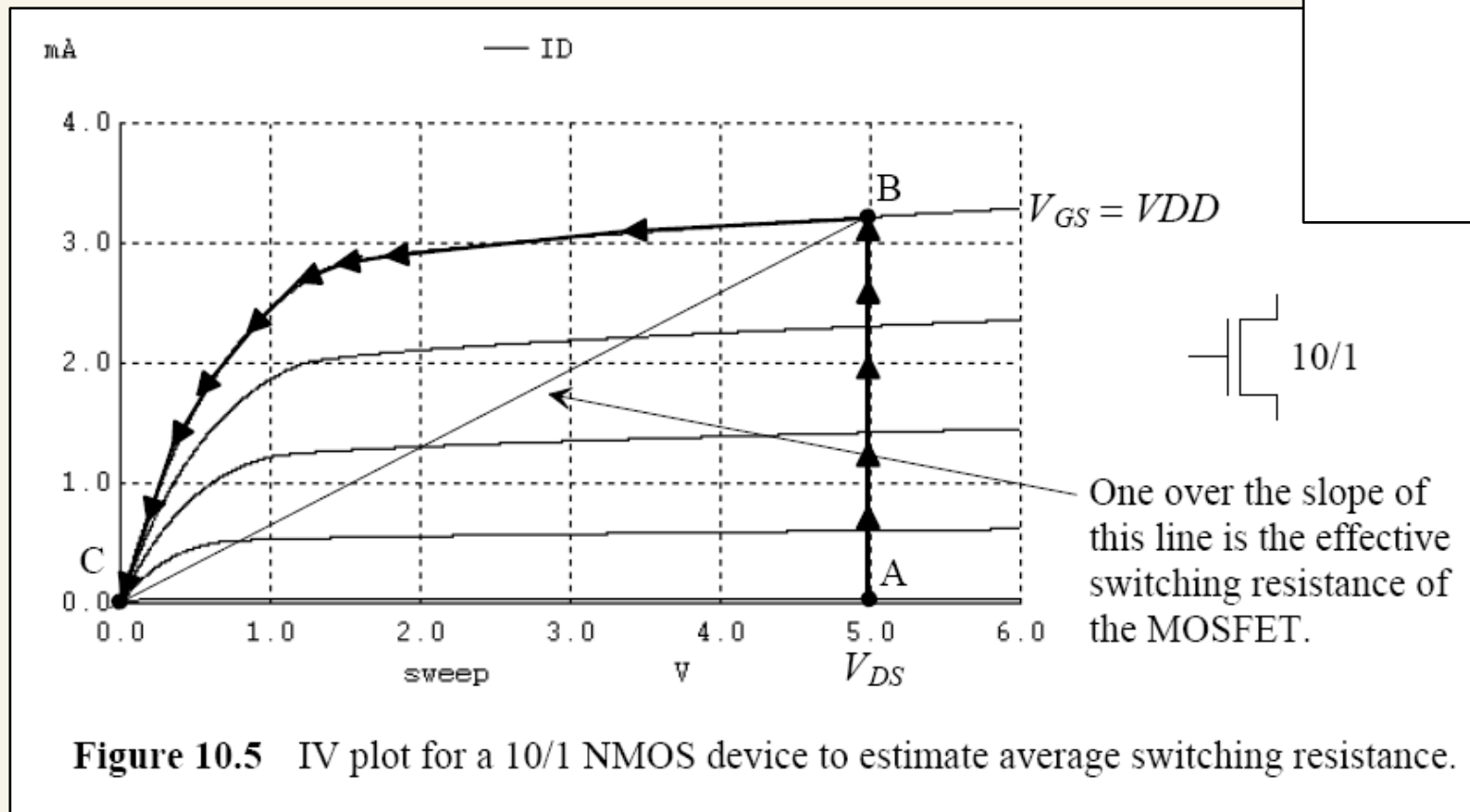


$$Q_{tot} = Q_{final} - Q_{init} = 2C \cdot VDD$$

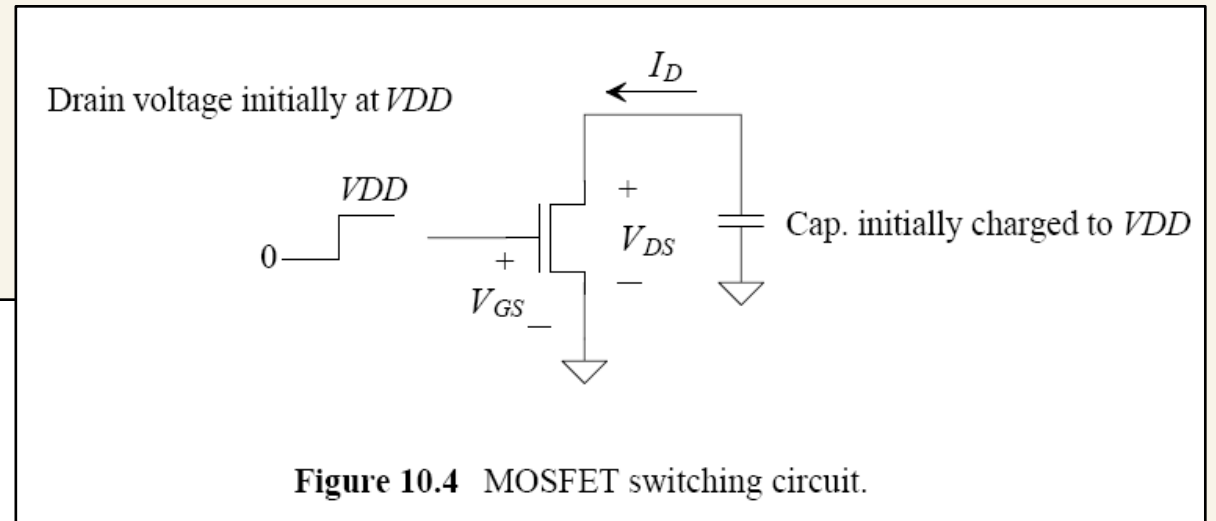


The Digital MOSFET Model

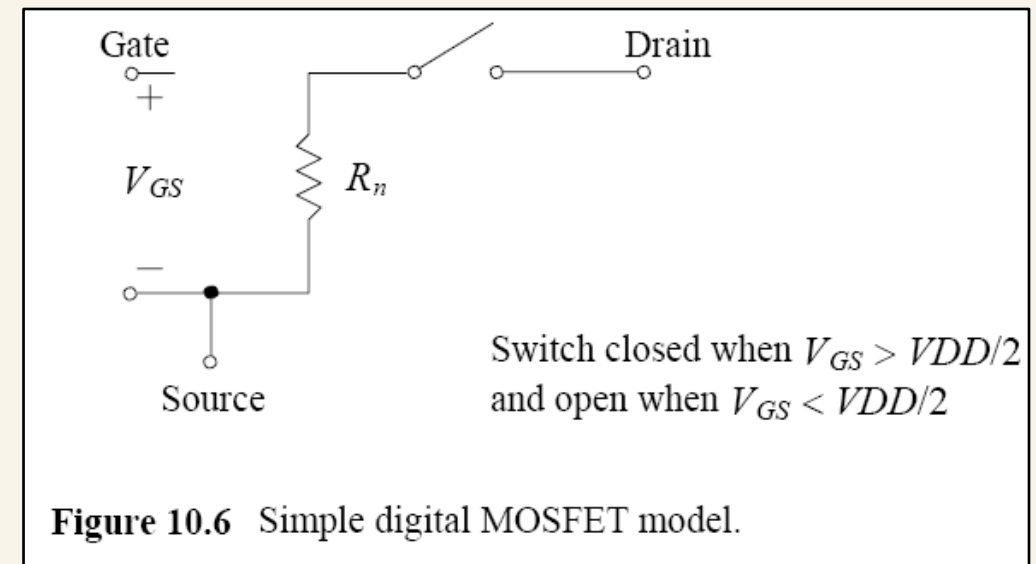
- Effective Switching Resistance



$$R_n = R'_n \cdot \frac{L}{W} = \frac{V_{DD}}{I_{D,sat}} = \frac{5}{3.3 \text{ mA}} \rightarrow R'_n \approx 15 \text{ k}\Omega$$

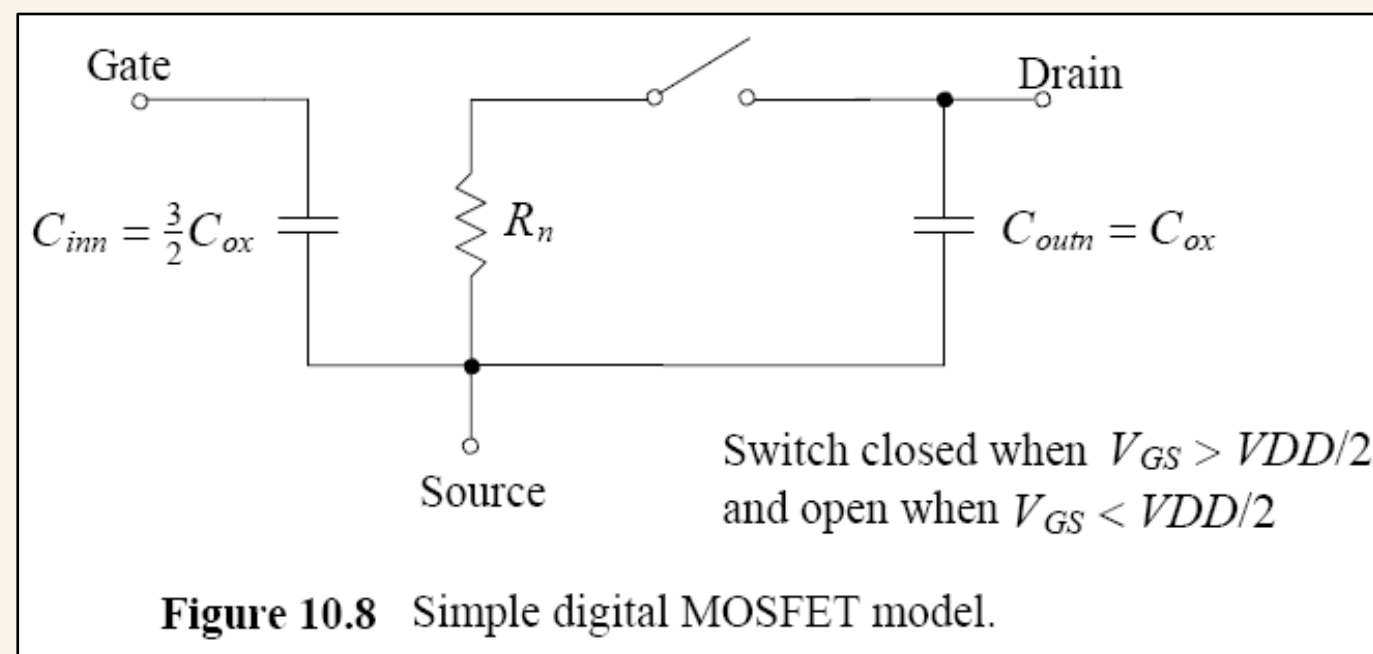
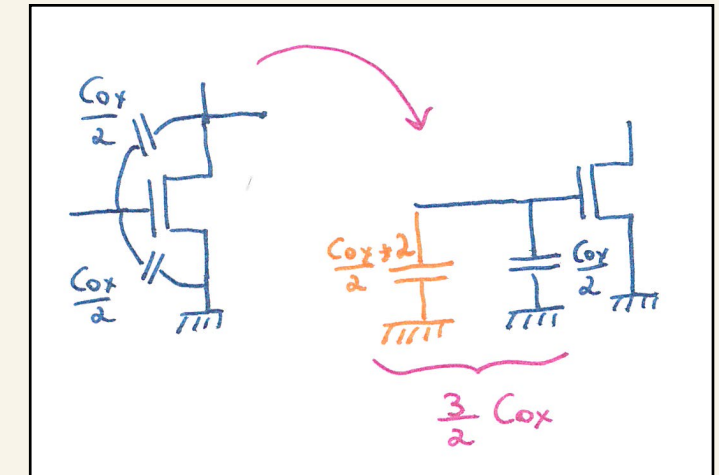
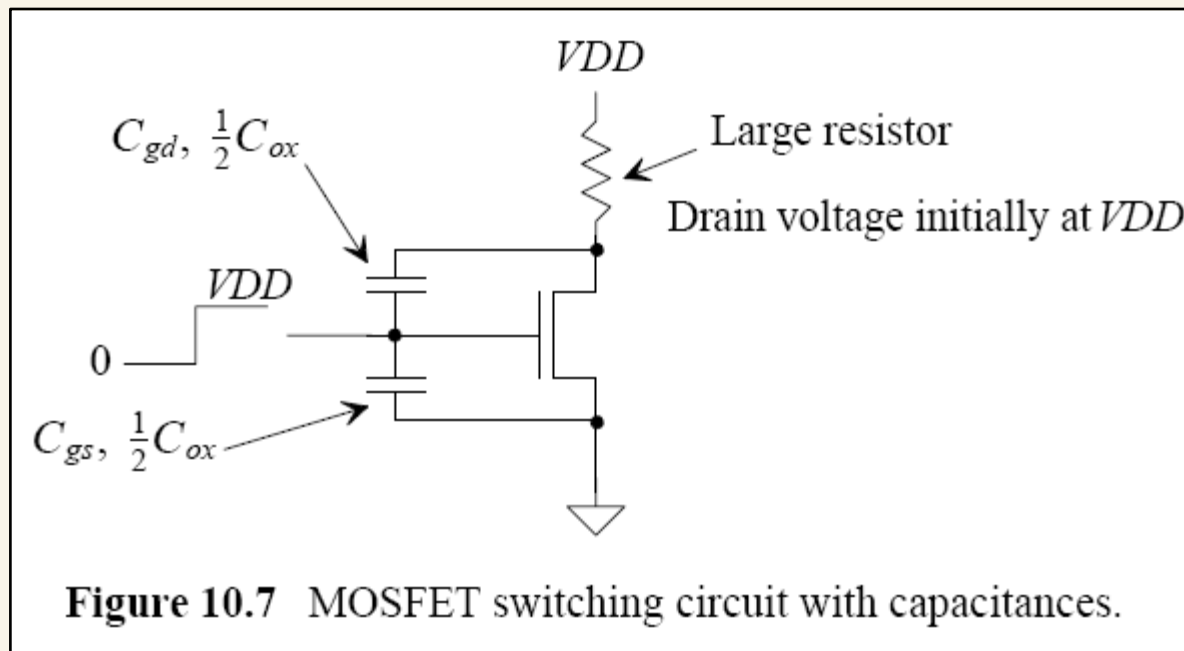


$$R_n = \frac{V_{DD}}{\frac{KP_n W}{2L} \cdot (V_{DD} - V_{THN})^2} = R'_n \cdot \frac{L}{W}$$



- Capacitive Effects

» Depletion capacitances are neglected when doing hand calculations



- Process Characteristic Time Constant

- Long-Channel Process $\tau_n = R_n C_{ox} = \frac{2L \cdot VDD}{KP_n W (VDD - V_{THN})^2} \cdot C'_{ox} WL \cdot (scale)^2 = \frac{2C'_{ox} \cdot VDD \cdot (L \cdot scale)^2}{KP_n \cdot (VDD - V_{THN})^2}$

- Short-Channel Process $\tau_n = R_n C_{ox} = \frac{2L \cdot VDD}{KP_n W (VDD - V_{THN})^2} \cdot C'_{ox} WL \cdot (scale)^2 = \frac{2C'_{ox} \cdot VDD \cdot (L \cdot scale)^2}{KP_n \cdot (VDD - V_{THN})^2}$

* Ne dépend pas de W
 * $\div L^2$
 * $\div \frac{1}{V_{DD}}$ ($V_{DD} \uparrow \tau \downarrow$)

Table 10.1 Digital model parameters used for hand calculations in the long- and short-channel CMOS processes used in this book. Note that the widths, W , and lengths, L , seen in this table are drawn lengths (minimum length is 1 while minimum width is 10).

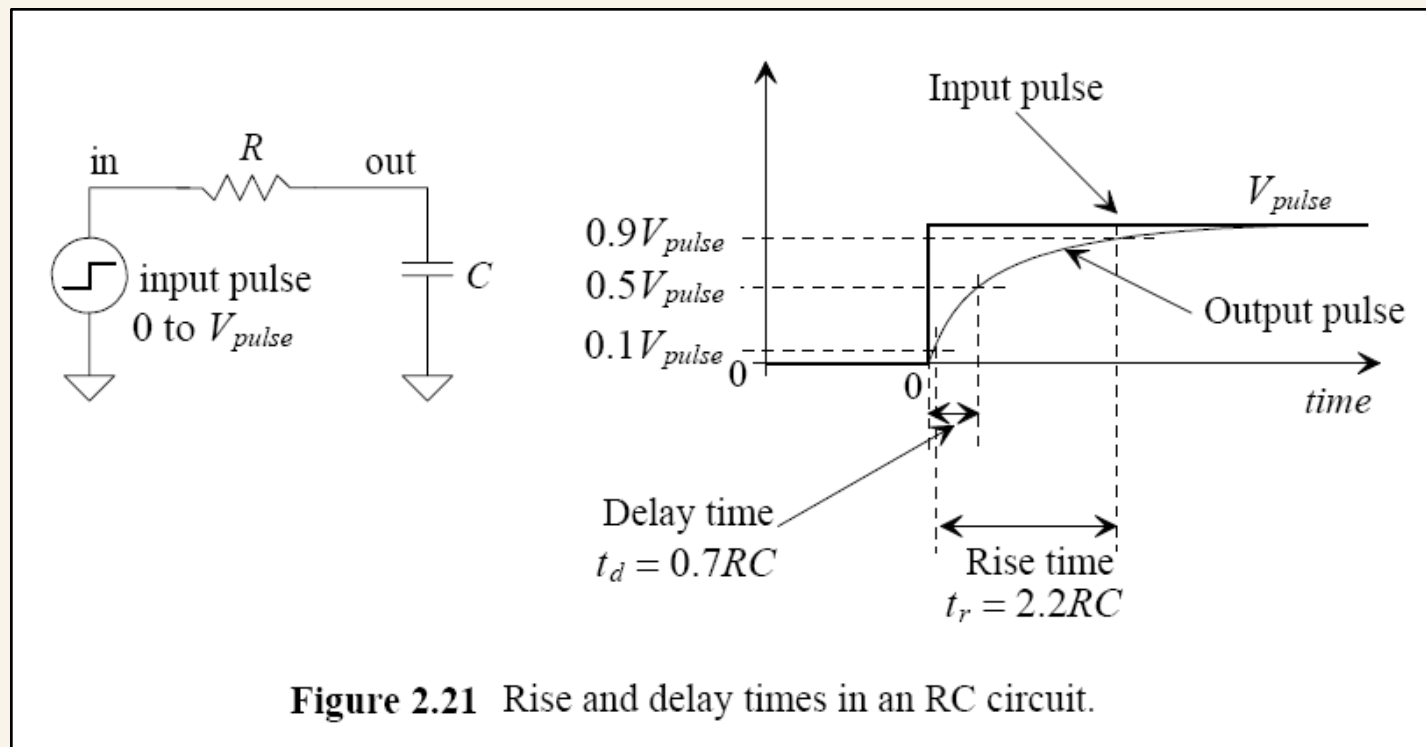
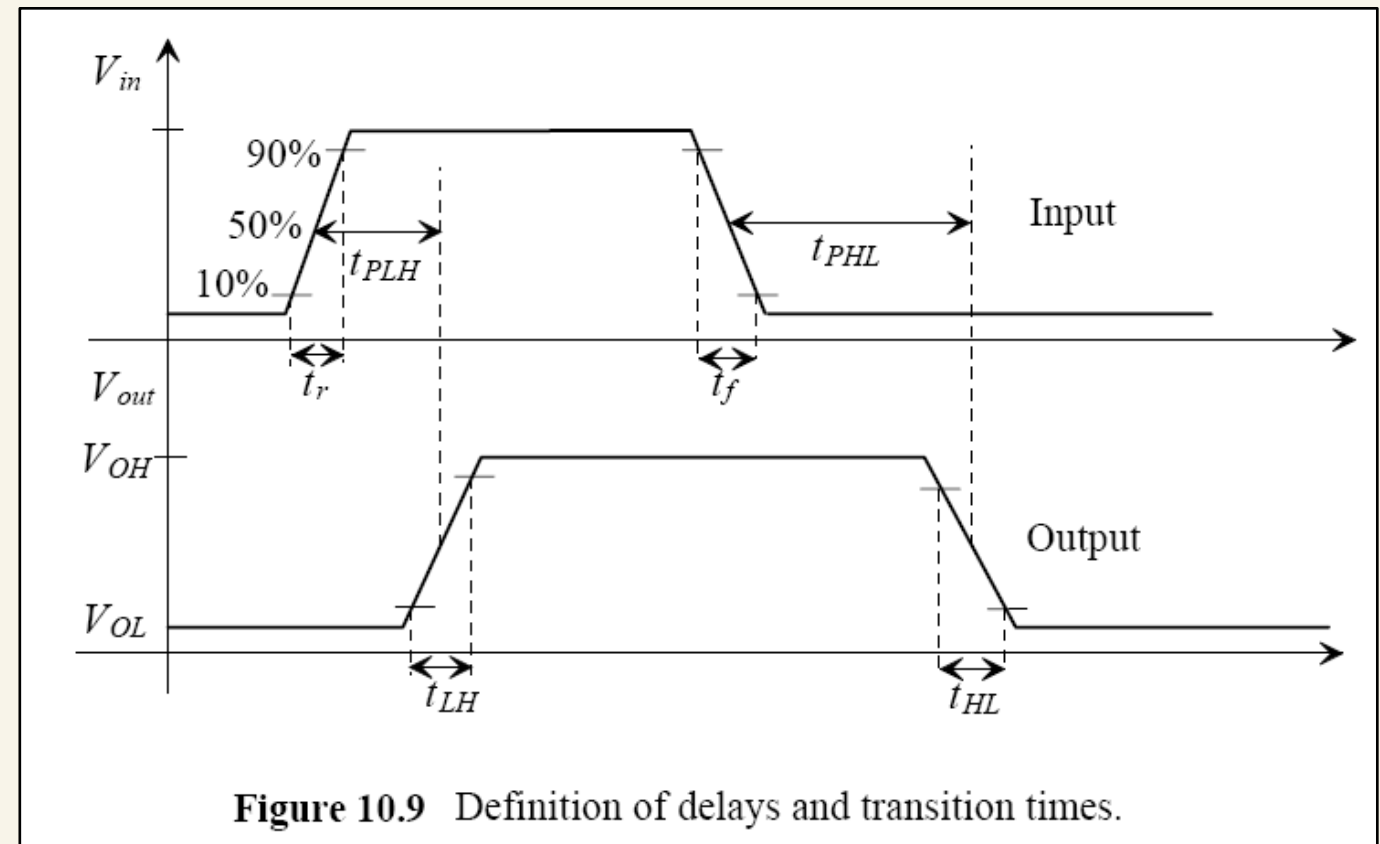
| Technology | R_n | R_p | Scale factor | $C_{ox} = C'_{ox} WL \cdot (scale)^2$ |
|-----------------------------------|-------------------|-------------------|-----------------|---------------------------------------|
| 1 μm (long-channel) | $15k \frac{L}{W}$ | $45k \frac{L}{W}$ | 1 μm | $(1.75 \text{ fF}) \cdot WL$ |
| 50 nm (short-channel) | $\frac{34k}{W}$ | $\frac{68k}{W}$ | 50 nm | $(62.5 \text{ aF}) \cdot WL$ |

- Delay and Transition Times

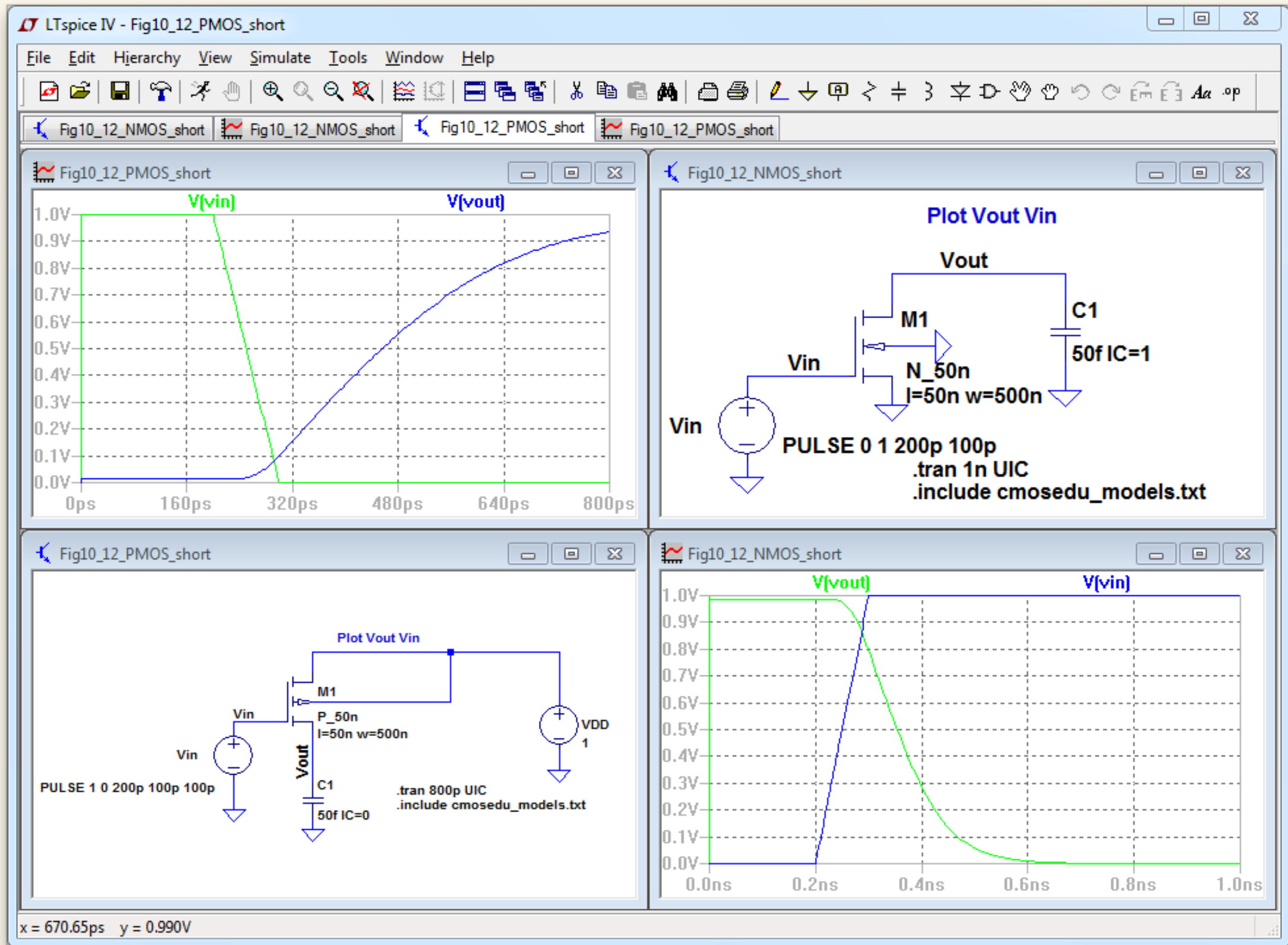
$$t_{PHL} \approx 0.7 \cdot R_n \cdot C_{tot} \text{ and } t_{PLH} \approx 0.7 \cdot R_p \cdot C_{tot}$$

$$t_{HL} \approx 2.2 \cdot R_n \cdot C_{tot} \text{ and } t_{LH} \approx 2.2 \cdot R_p \cdot C_{tot}$$

Ref. Book p 50



- Example



- General Digital Design

Table 10.2 Parameters for general digital design using the long-channel (scale factor is 1 μm) or short-channel (scale factor of 50 nm) CMOS process **used in this book**.

| Technology | Drawn | Actual size | $R_{n,p}$ | $C_{ox,n,p}$ |
|----------------------|-------|-------------------------------------|-----------|--------------|
| NMOS (long-channel) | 10/1 | 10 μm by 1 μm | 1.5k | 17.5 fF |
| PMOS (long-channel) | 30/1 | 30 μm by 1 μm | 1.5k | 52.5 fF |
| | | | | |
| NMOS (short-channel) | 10/1 | 0.5 μm by 50 nm | 3.4k | 625 aF |
| PMOS (short-channel) | 20/1 | 1 μm by 50 nm | 3.4k | 1.25 fF |

The MOSFET Pass Gate

- The NMOS Pass Gate

» An NMOS device is good at passing a "0" and bad at passing a "1"

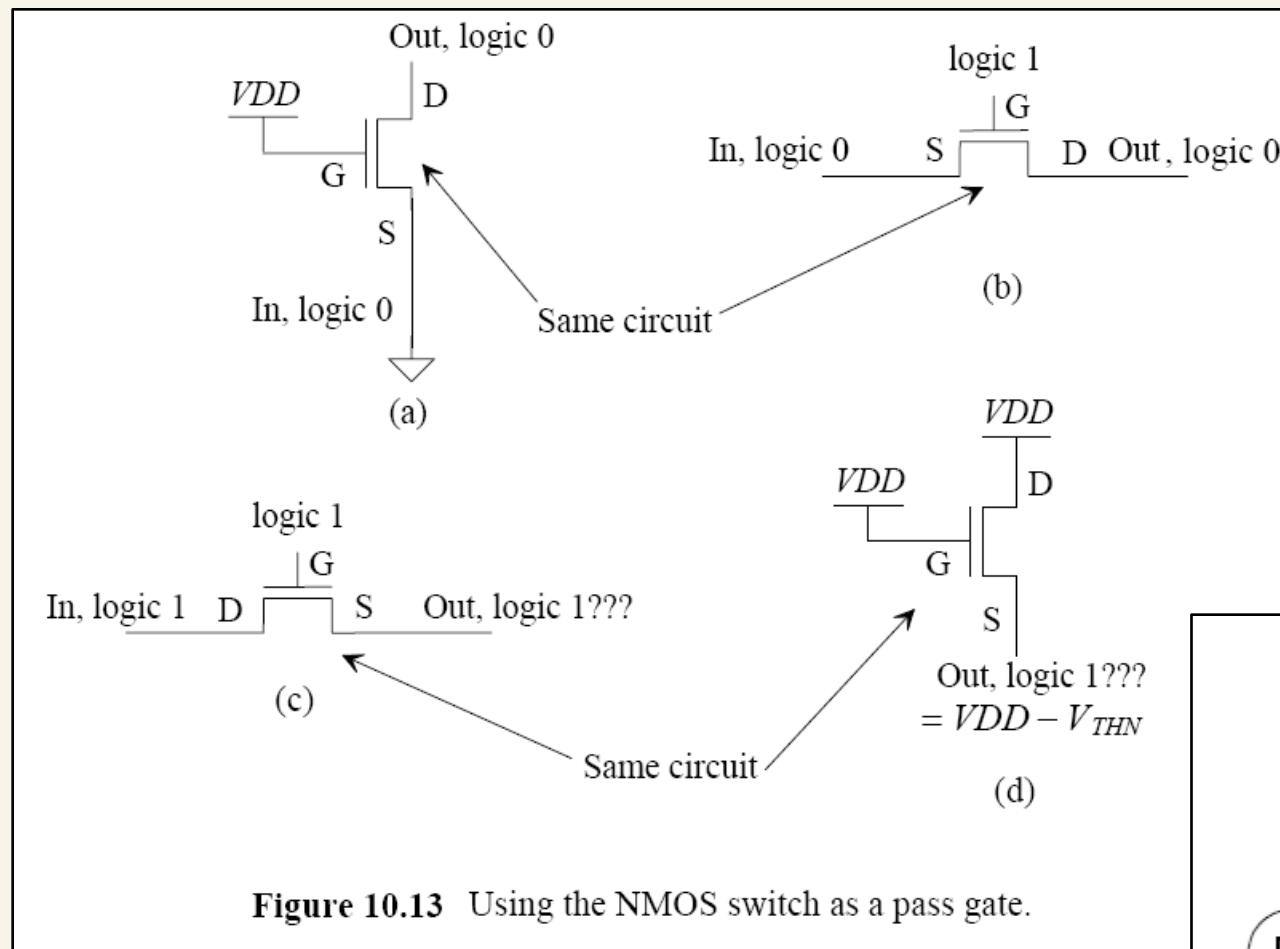


Figure 10.13 Using the NMOS switch as a pass gate.

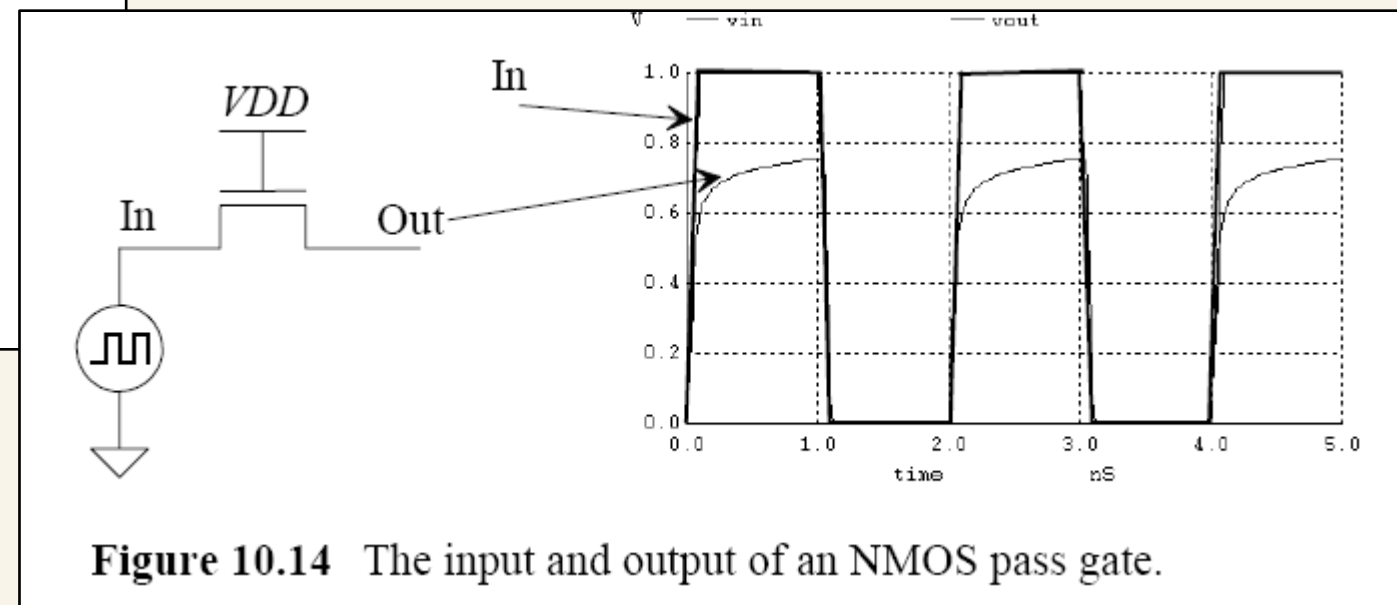
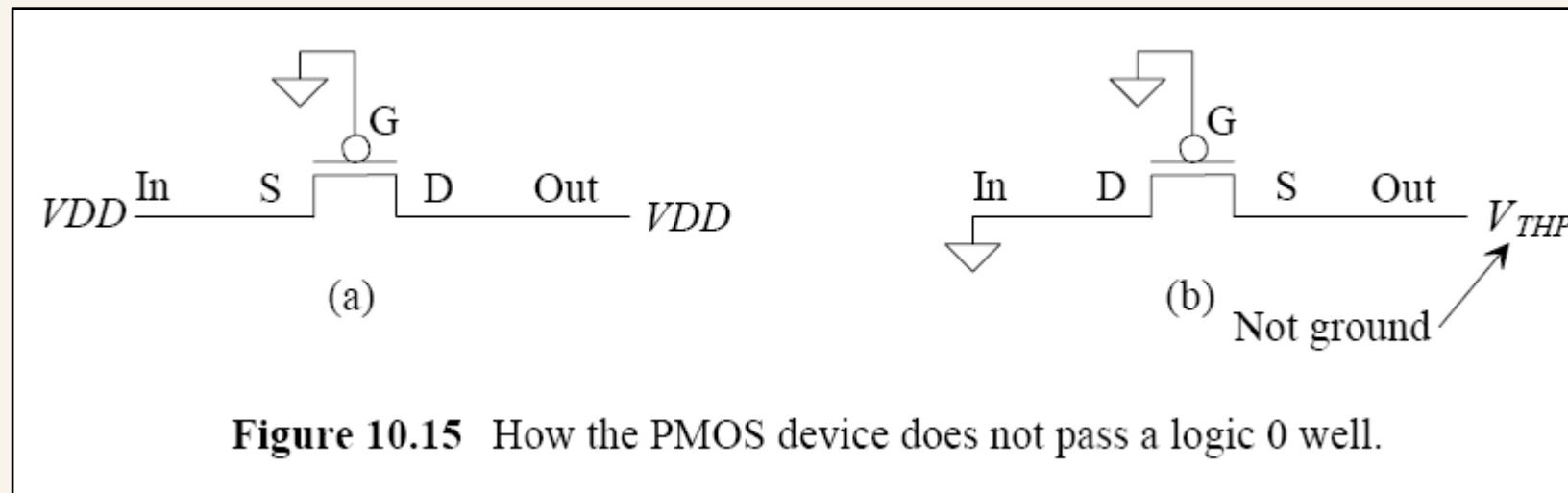


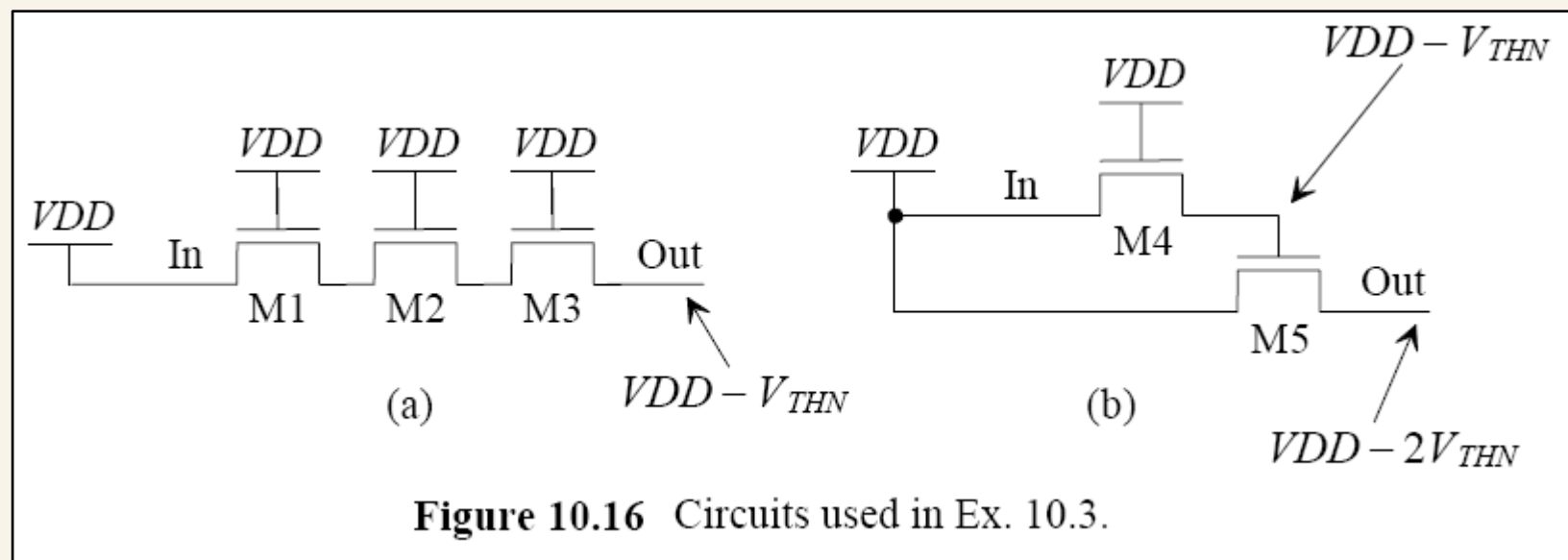
Figure 10.14 The input and output of an NMOS pass gate.

- The PMOS Pass Gate

» A PMOS device is good at passing a "1" and bad at passing a "0"

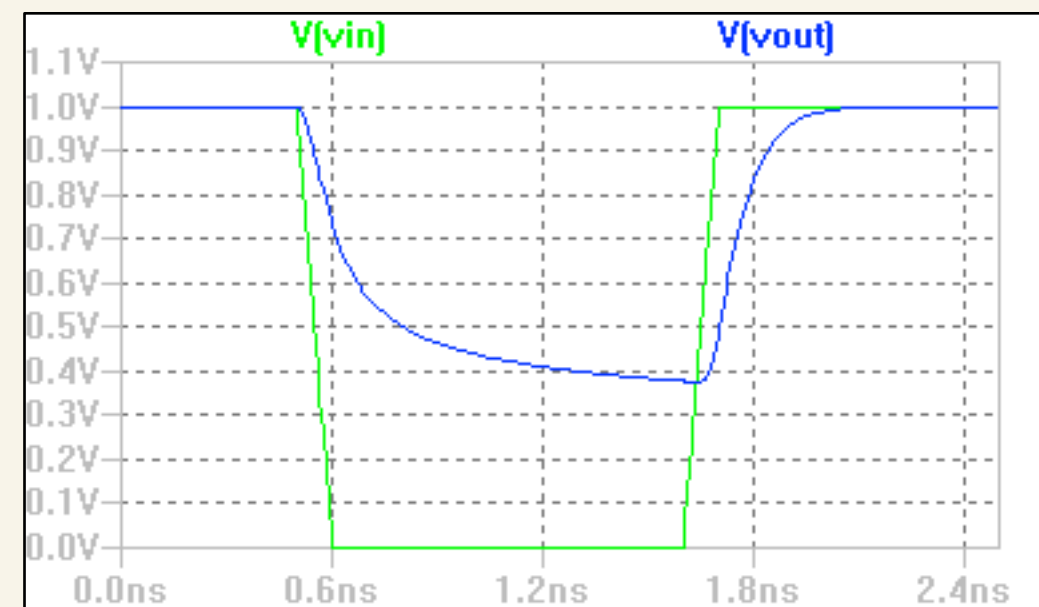
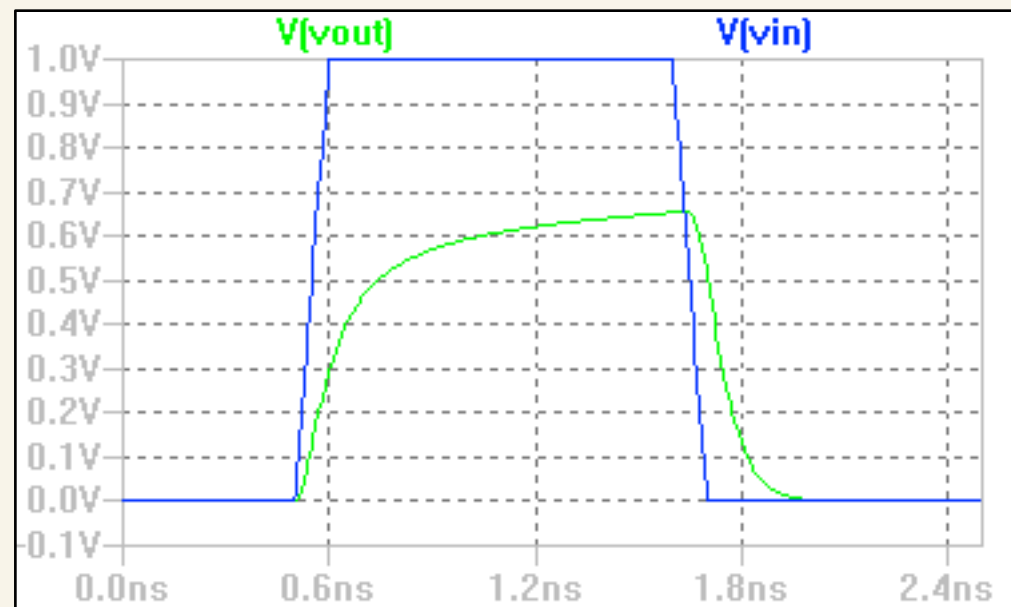
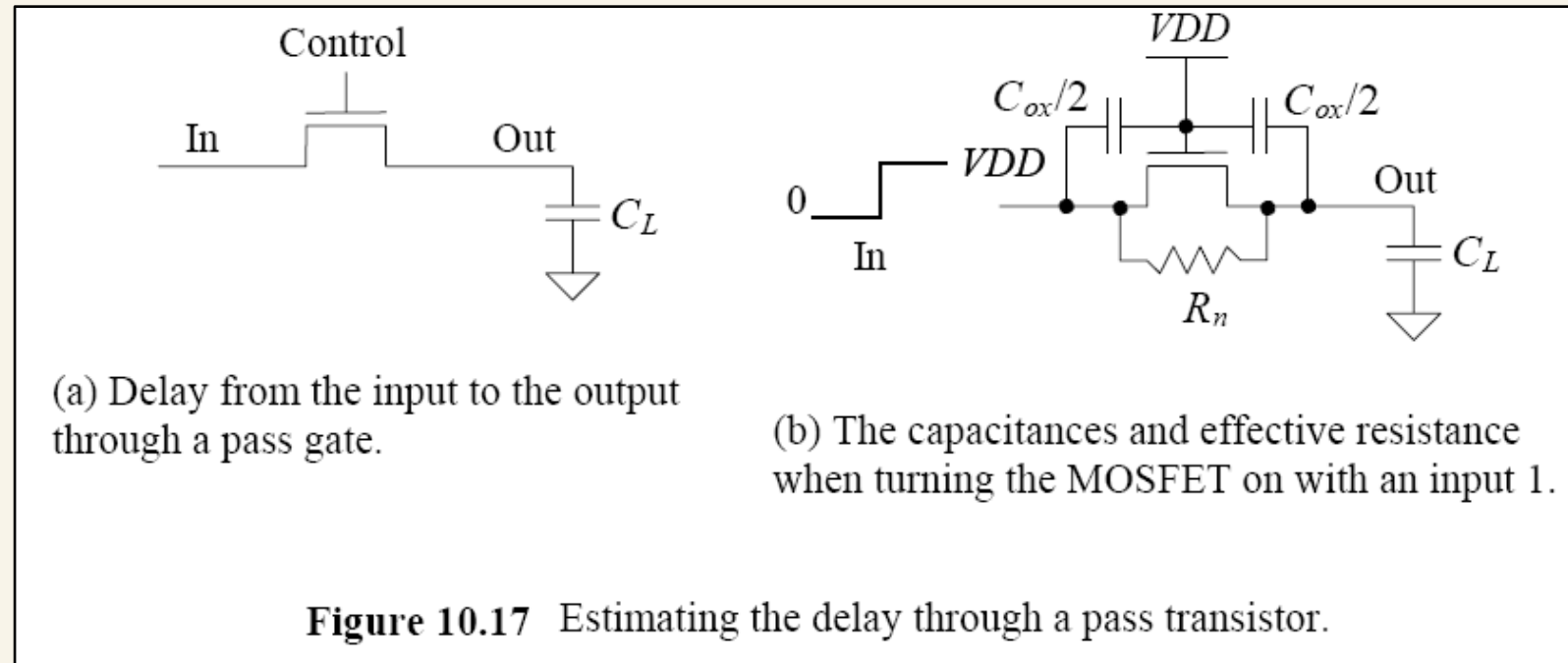


- Example

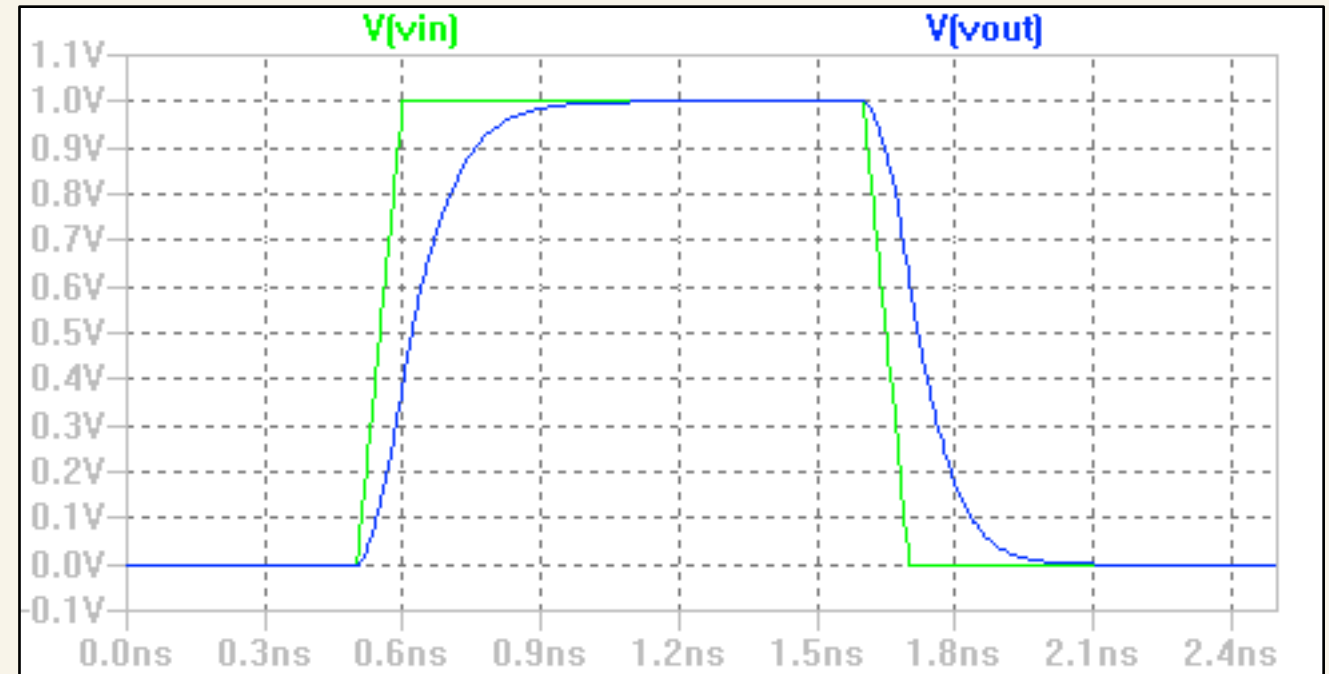
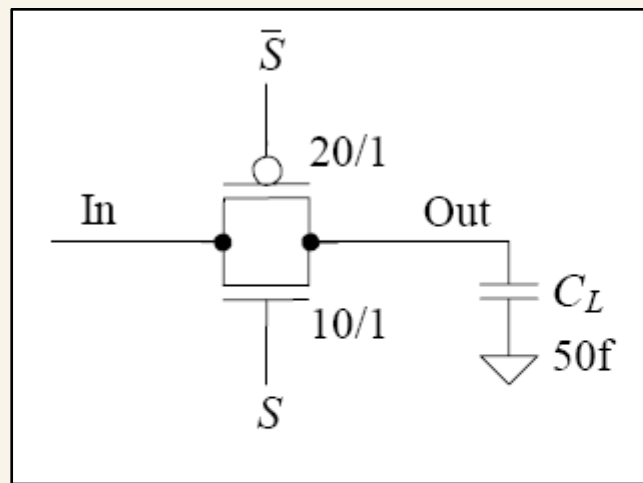


- Delay through a Pass Gate

$$t_{delay} = 0.7 \cdot R_n C_{tot} = 0.7 \cdot R_n \cdot \left(C_L + \frac{C_{ox}}{2} \right)$$



- The Transmission Gate (TG)



- Delay through Series-Connected PGs

$$t_{delay} \approx 0.35 \cdot R_n \cdot C_{ox} \cdot l^2$$

Ref. Book p 51

